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CY7C1041GN

4-Mbit (256K words × 16 bit) Static RAM

Features

- High speed
 □ t_{AA} = 10 ns / 15 ns
- Low active and standby currents
 Active current: I_{CC} = 38-mA typical
 Standby current: I_{SB2} = 6-mA typical
- Operating voltage range: 1.65 V to 2.2 V, 2.2 V to 3.6 V, and 4.5 V to 5.5 V
- 1.0-V data retention
- TTL-compatible inputs and outputs
- Pb-free 44-pin SOJ, 44-pin TSOP II, and 48-ball VFBGA packages

Functional Description

CY7C1041GN is high-performance CMOS fast static RAM Organized as 256K words by 16-bits.

Data writes are performed by asserting the Chip Enable (\overline{CE}) and Write Enable (\overline{WE}) inputs LOW, while providing the data on I/O₀ through I/O₁₅ and address on A₀ through A₁₇ pins. The Byte High Enable (BHE) and Byte Low Enable (BLE) inputs control write operations to the upper and lower bytes of the specified memory location. BHE controls I/O₈ through I/O₁₅ and BLE controls I/O₀ through I/O₇.

Data reads are performed by asserting the Chip Enable (\overline{CE}) and Output Enable (\overline{OE}) inputs LOW and providing the required address on the address lines. Read data is accessible on the I/O lines (I/O₀ through I/O₁₅). Byte accesses can be performed by asserting the required byte enable signal (BHE or BLE) to read either the upper byte or the lower byte of data from the specified address location.

All I/Os (I/O $_0$ through I/O $_{15}$) are placed in a high-impedance state during the following events:

- The device is deselected (CE HIGH)
- The control signals (OE, BLE, BHE) are de-asserted

The logic block diagram is on page 2.

Product Portfolio

Product			Speed Power Diss						
	Range	V _{CC} Range (V)	(ns)	Operating	l I _{CC} , (mA)	Standby	l (mA)		
	Range	ACC Irange (A)	10/15		f _{max}	Standby, I _{SB2} (mA)			
			10/10	Typ ^[1]	Max	Typ ^[1]	Max		
CY7C1041GN18		1.65 V–2.2 V	15	-	40				
CY7C1041GN30	Industrial	2.2 V–3.6 V	10	38	45	6	8		
CY7C1041GN		4.5 V–5.5 V	10	38	45				

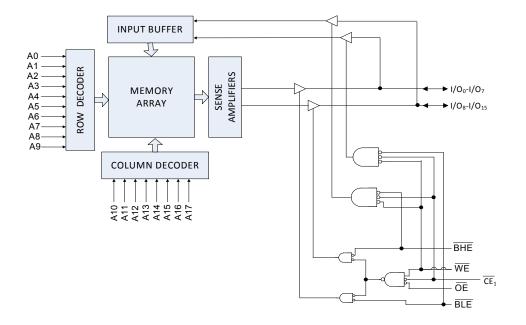
Notes

1. Typical values are included only for reference and are not guaranteed or tested. Typical values are measured at V_{CC} = 1.8 V (for a V_{CC} range of 1.65 V–2.2 V), V_{CC} = 3 V (for a V_{CC} range of 2.2 V–3.6 V), and V_{CC} = 5 V (for a V_{CC} range of 4.5 V–5.5 V), T_A = 25 °C.

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Logic Block Diagram – CY7C1041GN





CY7C1041GN

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Pin Configurations

Figure 1. 48-ball VFBGA (6 × 8 × 1.0 mm) pinout, Package/Grade ID: $BVXI^{[2, 3]}$

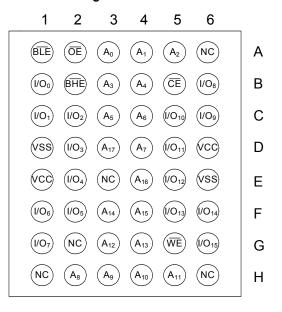
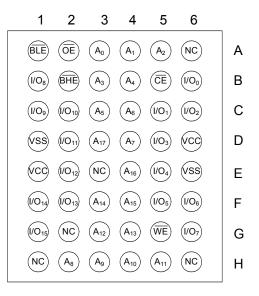


Figure 2. 48-ball VFBGA (6 × 8 × 1.0 mm) pinout, Package/Grade ID: BVJXI^[2]





_				
A0	1	\bigcirc	44	■ A17
A1	2		43	■ A16
A2	3		42	A15
A3 =	4		41	/OE
A4	5		40	/BHE
/CE	6		39	/BLE
I/O0 =	7		38	■ I/O15
I/O1 =	8		37	■ I/O14
I/O2 =	9	44- pin TSOP	ı,36∎	I/O13
I/O3	10	H pin 1001	35	I/O12 ■
VCC=	11		34	VSS
VSS■	12		33	VCC
I/O4 🗖	13		32	I/O11
I/O5 🗖	14		31	I/O10
I/O6 🗖	15		30	I/O9
I/07 🗖	16		29	I/O8
/WE =	17		28	NC
A5🖬	18		27	■ A14
A6 🗖	19		26	■ A13
A7 🖬	20		25	■ A12
A8	21		24	■ A11
A9 =	22		23	■ A10

Notes

2. NC pins are not connected internally to the die.

Package type BVJXI is JEDEC compliant compared to package type BVXI. The difference between the two is that the higher and lower byte I/Os (I/O_[7:0] and I/O_[15:8] balls are swapped.



Maximum Ratings

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage temperature65 °C to +150 °C
Ambient temperature with power applied–55 °C to +125 °C
Supply voltage on V_{CC} relative to $GND^{[4]}$ 0.5 V to V_{CC} + 0.5 V
DC voltage applied to outputs in HI-Z State ^[4] 0.5 V to V _{CC} + 0.5 V DC input voltage ^[4] 0.5 V to V _{CC} + 0.5 V

Current into outputs (in LOW state)	20 mA
Static discharge voltage	
(MIL-STD-883, Method 3015)	. > 2001 V
Latch-up current	> 140 mA

Operating Range

Grade	Ambient Temperature	V _{CC}
Industrial	–40 °C to +85 °C	1.65 V to 2.2 V, 2.2 V to 3.6 V, 4.5 V to 5.5 V

DC Electrical Characteristics

Over the operating range of -40 °C to 85 °C

Devenueter	Deseri		Test Candit			10 ns / 15 ns	5	Unit
Parameter	Descri	ption	Test Conditions		Min	Min Typ ^[5] Ma		Unit
		1.65 V to 2.2 V	V_{CC} = Min, I_{OH} = -0.1 mA	٨	1.4	_	-	
		2.2 V to 2.7 V	V_{CC} = Min, I_{OH} = -1.0 mA	N N	2	_	-	
N/	, Output HIGH	2.7 V to 3.0 V	V_{CC} = Min, I_{OH} = -4.0 mA	N N	2.2	_	-	V
V _{OH}	voltage	3.0 V to 3.6 V	V_{CC} = Min, I_{OH} = -4.0 mA	N N	2.4	_	-	V
		4.5 V to 5.5 V	V_{CC} = Min, I_{OH} = -4.0 mA	N N	2.4	_	-	
		4.5 V to 5.5 V	V_{CC} = Min, I_{OH} = -0.1 mA	N N	$V_{CC} - 0.5^{[6]}$	_	-	
		1.65 V to 2.2 V	V_{CC} = Min, I_{OL} = 0.1 mA		-	_	0.2	
N/	Output LOW	2.2 V to 2.7 V	V_{CC} = Min, I_{OL} = 2 mA		-	_	0.4	v
V _{OL}	voltage	2.7 V to 3.6 V	V _{CC} = Min, I _{OL} = 8 mA		-	_	0.4	V
		4.5 V to 5.5 V	V _{CC} = Min, I _{OL} = 8 mA		-	_	0.4	
	Input HIGH	1.65 V to 2.2 V	-		1.4	_	$V_{CC} + 0.2^{[4]}$	
N /		2.2 V to 2.7 V	-		2	_	V _{CC} + 0.3 ^[4]	
V _{IH}	voltage	2.7 V to 3.6 V	-		2	_	V _{CC} + 0.3 ^[4]	
		4.5 V to 5.5 V	-		2	_	V _{CC} + 0.5 ^[4]	
		1.65 V to 2.2 V	-		-0.2 ^[4]	_	0.4	
N /		2.2 V to 2.7 V	-		-0.3 ^[4]	_	0.6	v
V _{IL}	Input LOW voltage	2.7 V to 3.6 V	-		-0.3 ^[4]	_	0.8	
		4.5 V to 5.5 V	-		-0.5 ^[4]	_	0.8	
I _{IX}	Input leakage curre	ent	$GND \leq V_{IN} \leq V_{CC}$		-1	_	+1	μA
I _{OZ}	Output leakage cur	rent	GND <u><</u> V _{OUT} <u><</u> V _{CC} , Outp	ut disabled	-1	_	+1	μA
-		Max V_{CC} , $I_{OUT} = 0$ mA,	f = 100 MHz	-	38	45		
ICC	Operating supply c	urrent	$\begin{array}{c} \text{Max V}_{\text{CC}}, \text{ I}_{\text{OUT}} = 0 \text{ mA}, \\ \text{CMOS levels} \end{array} \qquad \qquad \begin{array}{c} \text{f} = 100 \text{ M} \\ \text{f} = 66.7 \text{ N} \end{array}$		_	_	40	mA
I _{SB1}	Automatic CE powe	er-down current –	$\begin{array}{l} \text{Max } V_{CC}, \ \overline{CE} \geq V_{IH}, \\ V_{IN} \geq V_{IH} \ \text{or} \ V_{IN} \leq V_{IL}, \ \text{f} = \end{array}$	f _{MAX}	-	-	15	mA
I _{SB2}	Automatic CE powe	er-down current –	$\begin{array}{l} \text{Max V}_{\text{CC}}, \ \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.2 \\ \text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.2 \ \text{V or V}_{\text{IN}} \end{array}$	2 V, ≤ 0.2 V, f = 0	-	6	8	mA

Notes

4. $V_{IL(min)}$ = -2.0 V and $V_{IH(max)}$ = V_{CC} + 2 V for pulse durations of less than 20 ns.

Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = 1.8 V (for V_{CC} range of 1.65 V–2.2 V), V_{CC} = 3 V (for V_{CC} range of 2.2 V–3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V–5.5 V), T_A = 25 °C.

6. This parameter is guaranteed by design and not tested.



Capacitance

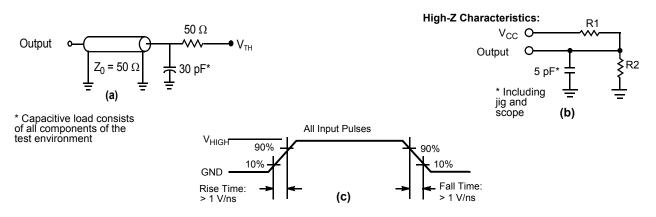
Parameter ^[7]	Description	Test Conditions	48-ball VFBGA	44-pin SOJ	44-pin TSOP II	Unit
C _{IN}	Input capacitance	T _A = 25 °C, f = 1 MHz,	10	10	10	pF
C _{OUT}	I/O capacitance	$V_{CC} = V_{CC(typ)}$	10	10	10	pF

Thermal Resistance

Parameter ^[7]	Description	Test Conditions	48-ball VFBGA	44-pin SOJ	44-pin TSOP II	Unit
(H)		Still air, soldered on a 3 × 4.5 inch, four-layer	31.35	55.37	68.85	°C/W
		printed circuit board	14.74	30.41	15.97	°C/W

AC Test Loads and Waveforms





Parameters	1.8 V	3.0 V	5.0 V	Unit
R1	1667	317	317	Ω
R2	1538	351	351	Ω
V _{TH}	0.9	1.5	1.5	V
V _{HIGH}	1.8	3	3	V

Notes

- 7. Tested initially and after any design or process changes that may affect these parameters.
- 8. Full-device AC operation assumes a 100- μ s ramp time from 0 to V_{CC(min)} and a 100- μ s wait time after V_{CC} stabilization.



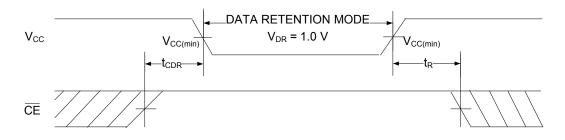
Data Retention Characteristics

Over the operating range of –40 $^\circ C$ to 85 $^\circ C$

Parameter	Description	Conditions	Min	Max	Unit
V _{DR}	V_{CC} for data retention		1	-	V
I _{CCDR}	Data retention current	$V_{CC} = 1.2 \text{ V}, \overline{CE} \ge V_{CC} - 0.2 \text{ V}^{[9]}, V_{IN} \ge V_{CC} - 0.2 \text{ V}, \text{ or } V_{IN} \le 0.2 \text{ V}$	-	8	mA
t _{CDR} ^[10]	Chip deselect to data retention time		0	-	ns
t _R ^[9, 10]	Operation recovery time	$V_{CC} \ge 2.2 V$	10	Ι	ns
'R' '		V _{CC} < 2.2 V	15	Ι	ns

Data Retention Waveform

Figure 5. Data Retention Waveform^[9]



Notes

9. Full-device operation requires linear V_{CC} ramp from V_{DR} to V_{CC(min)} \ge 100 µs or stable at V_{CC (min)} \ge 100 µs.

10. These parameters are guaranteed by design.



AC Switching Characteristics

Over the operating range of -40 °C to 85 °C

Parameter ^[11]	Description	10	10 ns			11
Parameter	Description	Min	Max	Min	Max	Unit
Read Cycle						
t _{RC}	Read cycle time	10	-	15	-	ns
t _{AA}	Address to data	-	10	_	15	ns
t _{OHA}	Data hold from address change	3	-	3	-	ns
t _{ACE}	CE LOW to data ^[12]	-	10	-	15	ns
t _{DOE}	OE LOW to data	-	4.5	_	8	ns
t _{LZOE}	OE LOW to low impedance ^[13, 14]	0	-	0	-	ns
t _{HZOE}	OE HIGH to HI-Z ^[13, 14]	-	5	_	8	ns
t _{LZCE}	CE LOW to low impedance ^[12, 13, 14]	3	_	3	-	ns
t _{HZCE}	CE HIGH to HI-Z ^[12, 13, 14]	-	5	_	8	ns
t _{PU}	CE LOW to power-up ^[12, 14, 15]	0	-	0	-	ns
t _{PD}	CE HIGH to power-down ^[12, 14, 15]	-	10	_	15	ns
t _{DBE}	Byte enable to data valid	-	4.5	_	8	ns
t _{LZBE}	Byte enable to low impedance ^[14]	0	-	0	-	ns
t _{HZBE}	Byte disable to HI-Z ^[14]	-	6	_	8	ns
Write Cycle ^{[15}	5, 16]					
t _{WC}	Write cycle time	10	_	15	-	ns
t _{SCE}	CE LOW to write end ^[12]	7	-	12	-	ns
t _{AW}	Address setup to write end	7	-	12	-	ns
t _{HA}	Address hold from write end	0	-	0	-	ns
t _{SA}	Address setup to write start	0	-	0	-	ns
t _{PWE}	WE pulse width	7	-	12	-	ns
t _{SD}	Data setup to write end	5	-	8	-	ns
t _{HD}	Data hold from write end	0	-	0	-	ns
t _{LZWE}	WE HIGH to low impedance [13, 14]	3	-	3	-	ns
t _{HZWE}	WE LOW to HI-Z ^[13, 14]	_	5	-	8	ns
t _{BW}	Byte Enable to write end	7	-	12	-	ns

Notes

- 11. Test conditions assume a signal transition time (rise/fall) of 3 ns or less, timing reference levels of 1.5 V (for V_{CC} ≥ 3 V) and V_{CC}/2 (for V_{CC} < 3 V), and input pulse levels of 0 to 3 V (for V_{CC} ≥ 3 V) and 0 to V_{CC} (for V_{CC} < 3 V). Test conditions for the read cycle use output loading, as shown in part (a) of Figure 4 on page 6, unless specified otherwise.
- 12. For all dual chip enable devices, \overline{CE} is the logical combination of \overline{CE}_1 and CE_2 . When \overline{CE}_1 is LOW and CE_2 is HIGH, \overline{CE} is LOW; when \overline{CE}_1 is HIGH or CE_2 is LOW, \overline{CE} is HIGH.
- 13. t_{HZOE}, t_{HZCE}, t_{HZOE}, t_{LZOE}, t_{LZOE}, t_{LZOE}, t_{LZWE}, and t_{LZBE} are specified with a load capacitance of 5 pF, as shown in part (b) of Figure 4 on page 6. Transition is measured ±200 mV from steady state voltage.

14. These parameters are guaranteed by design and are not tested.

15. The internal write time of the memory is defined by the overlap of $\overline{WE} = V_{IL}$, $\overline{CE} = V_{IL}$, and \overline{BHE} or $\overline{BLE} = V_{IL}$. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.

16. The minimum write cycle pulse width in Write Cycle No. 2 (WE Controlled, OE LOW) should be equal to sum of t_{SD} and t_{HZWE}.



Switching Waveforms

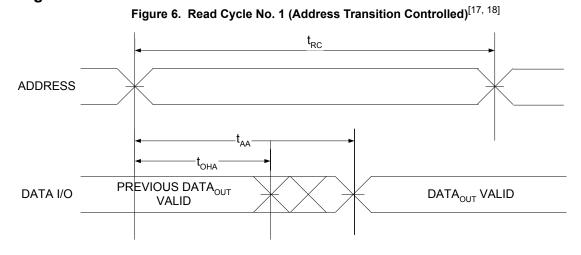
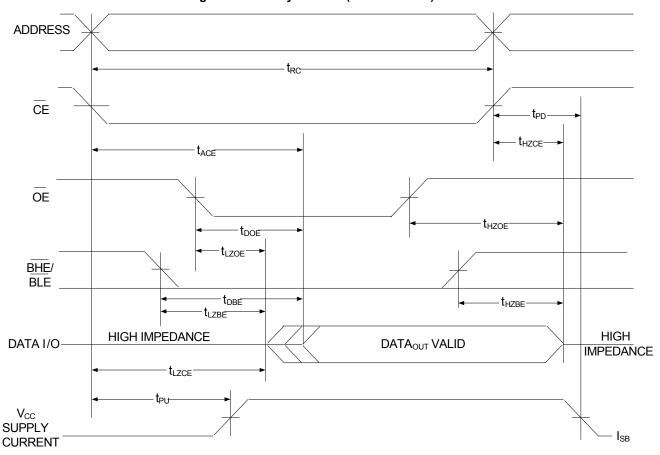


Figure 7. Read Cycle No. 2 (OE Controlled)^[18, 19]



Notes

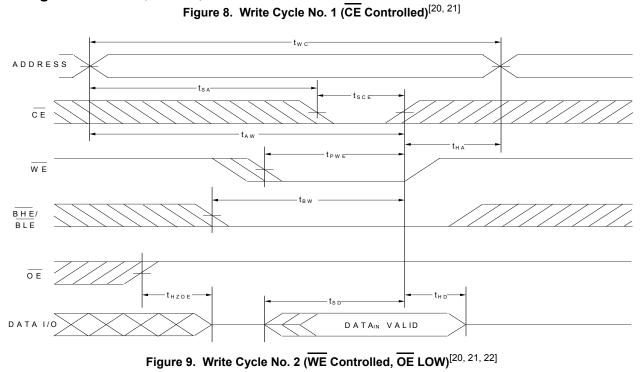
17. <u>The</u> device is continuously selected, $\overline{OE} = V_{IL}$, $\overline{CE} = V_{IL}$, \overline{BHE} or \overline{BLE} or both = V_{IL} .

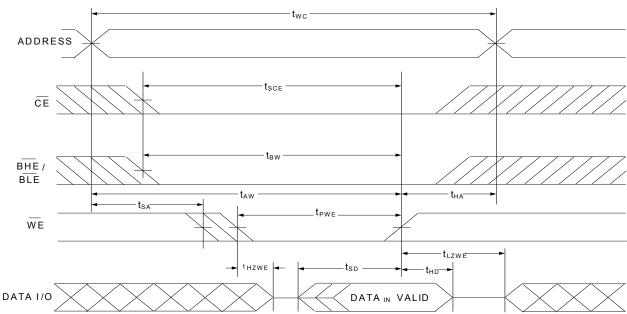
18. $\overline{\text{WE}}$ is HIGH for the read cycle.

19. Address valid prior to or coincident with $\overline{\text{CE}}$ LOW transition.



Switching Waveforms (continued)





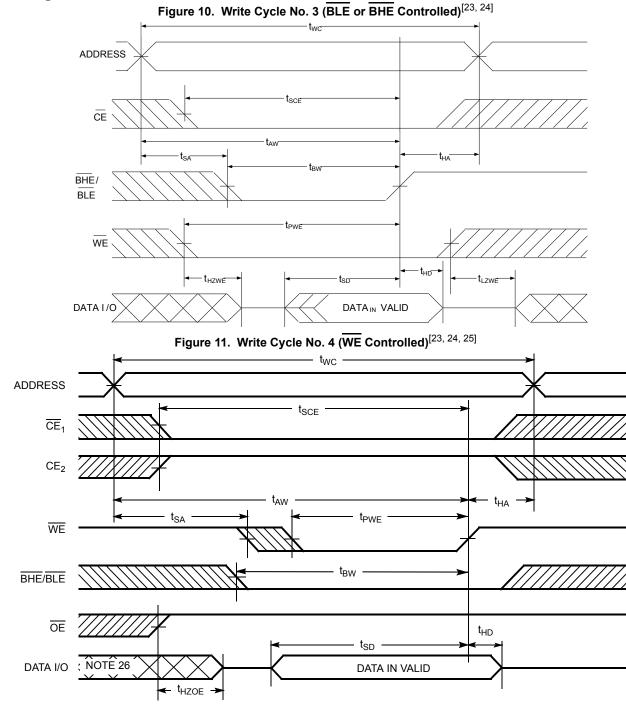
Notes

- 20. The internal write time of the memory is defined by the overlap of $\overline{WE} = V_{IL}$, $\overline{CE} = V_{IL}$, and \overline{BHE} or $\overline{BLE} = V_{IL}$. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.
- 21. Data I/O is in HI-Z state if $\overline{CE} = V_{IH}$, or $\overline{OE} = V_{IH}$, or \overline{BHE} , and/or $\overline{BLE} = V_{IH}$.

22. The minimum write cycle pulse width should be equal to sum of t_{SD} and t_{HZWE} .



Switching Waveforms (continued)



Notes

- 23. The internal write time of the memory is defined by the overlap of WE = V_{IL}, CE = V_{IL}, and BHE or BLE = V_{IL}. These signals must be LOW to initiate a write, and the HIGH transition of any of these signals can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.
- 24. Data I/O is in HI-Z state if $\overline{CE} = V_{IH}$, or $\overline{OE} = V_{IH}$, or \overline{BHE} , and/or $\overline{BLE} = V_{IH}$.
- 25. Data I/O is high impedance if $\overline{OE} = V_{IH}$.
- 26. During this period the I/Os are in output state. Do not apply input signals.



Truth Table

CE	OE	WE	BLE	BHE	I/O ₀ I/O ₇	I/O ₈ –I/O ₁₅	Mode	Power
Н	X ^[27]	X ^[27]	X ^[27]	X ^[27]	HI-Z	HI-Z	Power down	Standby (I _{SB})
L	L	Н	L	L	Data out	Data out	Read all bits	Active (I _{CC})
L	L	Н	L	Н	Data out	HI-Z	Read lower bits only	Active (I _{CC})
L	L	Н	Н	L	HI-Z	Data out	Read upper bits only	Active (I _{CC})
L	Х	L	L	L	Data in	Data in	Write all bits	Active (I _{CC})
L	Х	L	L	Н	Data in	HI-Z	Write lower bits only	Active (I _{CC})
L	Х	L	Н	L	HI-Z	Data in	Write upper bits only	Active (I _{CC})
L	Н	Н	Х	Х	HI-Z	HI-Z	Selected, outputs disabled	Active (I _{CC})

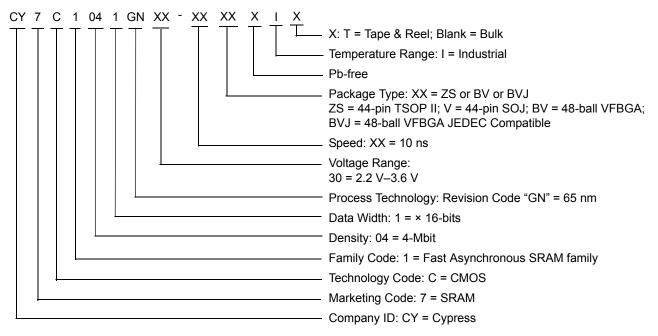
Notes 27. The input voltage levels on these pins should be either at V_{IH} or $V_{\text{IL}}.$



Ordering Information

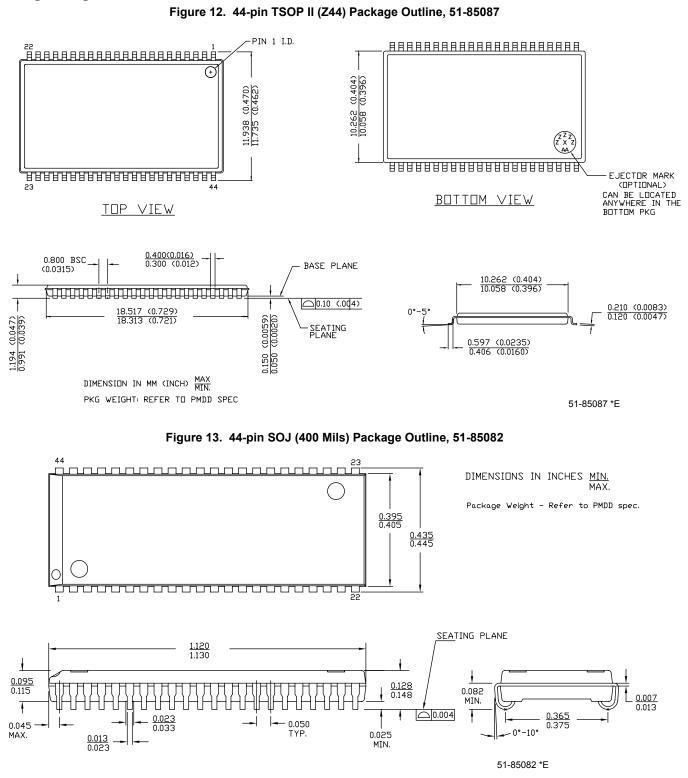
Speed (ns)	Voltage Range	Ordering Code	Package Diagram	Package Type (all Pb-free)	Operating Range	
	2.2 V–3.6 V	CY7C1041GN30-10ZSXI	51-85087	44-pin TSOP II		
		CY7C1041GN30-10ZSXI	51-85087	44-pin TSOP II, Tape & Reel		
		CY7C1041GN30-10VXI	51-85082	44-pin SOJ		
		CY7C1041GN30-10VXIT	51-85082	44-pin SOJ, Tape & Reel		
		CY7C1041GN30-10BVXI	51-85150	48-ball VFBGA (6 × 8 × 1.0 mm)	Industrial	
10		CY7C1041GN30-10BVXIT	51-85150	48-ball VFBGA (6 × 8 × 1.0 mm), Tape & Reel		
10		CY7C1041GN30-10BVJXI	51-85150	48-ball VFBGA (6 × 8 × 1.0 mm), JEDEC Compatible		
			CY7C1041GN30-10BVJXIT	51-85150	48-ball VFBGA (6 × 8 × 1.0 mm), JEDEC Compatible, Tape & Reel	
	4.5 V–5.5 V	CY7C1041GN-10ZSXI	51-85087	44-pin TSOP II		
		CY7C1041GN-10ZSXIT	51-85087	44-pin TSOP II, Tape & Reel		
		CY7C1041GN-10VXI	51-85082	44-pin SOJ	1	
		CY7C1041GN-10VXIT	51-85082	44-pin SOJ, Tape & Reel		

Ordering Code Definitions





Package Diagrams

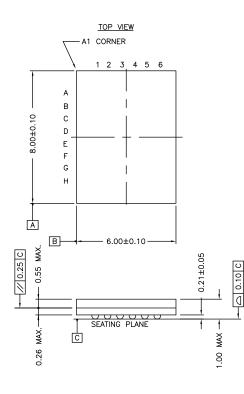


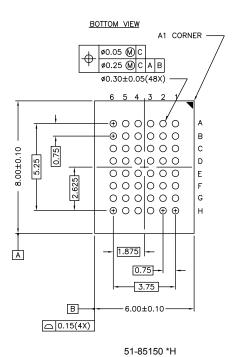




Package Diagrams (continued)







NOTE:

PACKAGE WEIGHT: See Cypress Package Material Declaration Datasheet (PMDD) posted on the Cypress web.





Acronyms

Acronym	Description		
BHE	byte high enable		
BLE	byte low enable		
CE	chip enable		
CMOS	complementary metal oxide semiconductor		
I/O	input/output		
OE	output enable		
SRAM	static random-access memory		
TSOP	thin small outline package		
TTL	transistor-transistor logic		
VFBGA	very fine-pitch ball grid array		
WE	write enable		

Document Conventions

Units of Measure

Symbol	Unit of Measure
°C	Degrees Celsius
MHz	megahertz
μΑ	microamperes
μS	microseconds
mA	milliamperes
mm	millimeters
ns	nanoseconds
Ω	ohms
%	percent
pF	picofarads
V	volts
W	watts



Document History Page

Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change
**	5074414	NILE	01/06/2016	New data sheet.
*A	5082573	NILE	01/12/2016	Updated Logic Block Diagram – CY7C1041GN. Updated Ordering Information: Updated part numbers.
*В	5120171	VINI	02/01/2016	Updated Logic Block Diagram – CY7C1041GN.
*C	5322961	VINI	06/24/2016	Updated Ordering Information: Updated part numbers. Updated to new template.
*D	5431651	NILE	09/09/2016	Updated Ordering Information: Updated part numbers. Added Tape & Reel ordering codes. Updated DC Electrical Characteristics: Enhanced V _{OH} for voltage range 3.0 ^N to 3.6V from 2.2V to 2.4V. Enhanced V _{IH} for voltage range 4.5V to 5.5V from 2.2V to 2.0V. Updated Note 4. Updated Copyright and Disclaimer.



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